Special Issue

Computer Vision in Automatic Detection and Identification

Message from the Guest Editors

With recent advances, computer vision and Artificial Intelligence (AI) approaches have demonstrated great promise in Industry 4.0, smart agriculture, medicine, and other fields. The recent development and application of big data and AI approaches in particular boost computer-vision-based detection and identification. There are many theories, algorithms, and application approaches that have been proposed to solve challenges in the domains of science, engineering, and society. The purpose of this Special Issue is to report on advances and applications in computer-vision-based detection and identification. We welcome original research and review articles. Potential topics include but are not limited to the following:

- Detection and identification;
- Image processing;
- Object detection and segmentation;
- Computer vision tools and applications;
- Pattern recognition;
- Digital image techniques;
- Multispectral image-based detection

Guest Editors

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Deadline for manuscript submissions

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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